



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Hideto Ohnuma et al.

Art Unit : 2812

Serial No. : 09/925,512

Examiner : Richard A. Booth

Filed : August 10, 2001

Title : METHOD OF MANUFACTURING A SEMICONDUCTOR DEVICE

MAIL STOP AMENDMENT

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

Submitted herewith is an English translation of the following foreign language references, or portions thereof:

Desig. ID	Source
AR	JAPAN 10-32327 - Full English translation

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: _____

8/15/05

John F. Hayden
Reg. No. 37,640

Fish & Richardson P.C.
1425 K Street, N.W.
11th Floor
Washington, DC 20005-3500
Telephone: (202) 783-5070
Facsimile: (202) 783-2331

40289992.doc

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-068001	Application No. 09/925,512
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hideto Ohnuma et al.	
		Filing Date August 10, 2001	Group Art Unit 2812

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002/0146627 A1	10/10/2002	Suleski et al.			06/03/2002
	AB	6,071,652	06/06/2000	Feldman et al.			03/20/1998
	AC	6,365,917 B1	04/02/2002	Yamazaki			11/16/1999
	AD	6,420,073 B1	07/16/2002	Suleski et al.			05/31/2000
	AE	6,515,336 B1	02/04/2003	Suzawa et al.			09/18/2000
	AF	6,534,826 B2	03/18/2003	Yamazaki			04/27/2000
	AG	6,541,294 B1	04/01/2003	Yamazaki et al.			07/18/2000
	AH	6,613,620 B2	09/02/2003	Fujimoto et al.			07/30/2001
	AI	6,638,667 B2	10/28/2003	Suleski et al.			06/03/2002
	AJ	6,646,287 B1	11/11/2003	Ono et al.			11/17/2000
	AK	6,660,462 B1	12/09/2003	Fukuda			04/05/2000
	AL	6,664,145 B1	12/16/2003	Yamazaki et al.			07/19/2000
	AM	6,707,068 B2	03/16/2004	Fujimoto et al.			06/09/2003
	AN	6,773,996 B2	08/10/2004	Suzawa et al.			05/10/2001
	AO	6,828,586 B2	12/07/2004	Fujimoto et al.			03/05/2004
	AP	6,872,604 B2	03/29/2005	Yamazaki et al.			06/04/2001
	AQ	6,909,114 B1	06/21/2005	Yamazaki			11/04/1999

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AR	10-032327	02/03/1998	JAPAN			FULL	

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AS	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	